Ā/B

1A [ 2

1Y Π

2A [

GND [ 8

1B 🛛 3

4

5 2B [

6 2Y 17

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16 Vcc

15 G

14**0** 4A

13 **1** 4B

12 4Y

11 🛛 3A

10 3B

9 🛛 3Y

D, DB, OR PW PACKAGE (TOP VIEW)

- EPIC<sup>™</sup> (Enhanced-Performance Implanted **CMOS) Submicron Process**
- Typical V<sub>OLP</sub> (Output Ground Bounce) < 0.8 V at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C
- Typical V<sub>OHV</sub> (Output V<sub>OH</sub> Undershoot) > 2 V at V<sub>CC</sub> = 3.3 V,  $T_A = 25^{\circ}C$
- Inputs Accept Voltages to 5.5 V
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Per Latch-Up Performan **JESD 17**
- Package Options Inc Small-Outline (D), Sh (DB), and Thin Shrink Small-Outline (PW) Packages

ce I	Exceed	ls 2	50 r	nA
lud	e Plas	tic		
nrin	k Sma	II-O	utlir	ne

#### description

This quadruple 2-line to 1-line data selector/multiplexer is designed for 1.65-V to 3.6-V V<sub>CC</sub> operation.

The SN74LVC157A features a common strobe ( $\overline{G}$ ) input. When the strobe is high, all outputs are low. When the strobe is low, a 4-bit word is selected from one of two sources and is routed to the four outputs. The device provides true data.

Inputs can be driven from either 3.3-V or 5-V devices. This feature allows the use of these devices as translators in a mixed 3.3-V/5-V system environment.

The SN74LVC157A is characterized for operation from -40°C to 85°C.

	INPU	INPUTS OUTPUT					
G	Ā/B	Α	В	Y			
Н	Х	Х	Х	L			
L	L	L	Х	L			
L	L	Н	Х	н			
L	Н	Х	L	L			
L	Н	Х	Н	н			

#### **FUNCTION TABLE**



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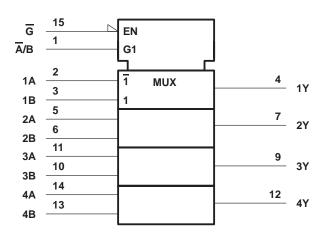
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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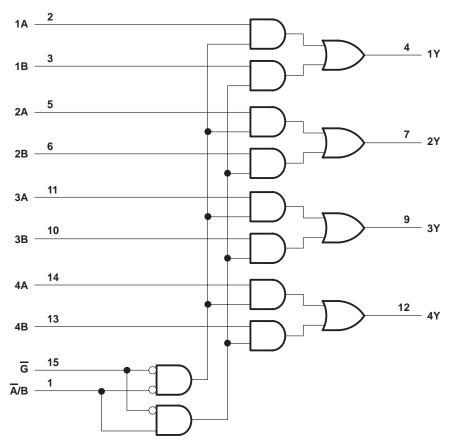
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## logic symbol<sup>†</sup>



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

## logic diagram (positive logic)





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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage range, $V_{CC}$ Input voltage range, $V_I$ (see Note 1) Output voltage range, $V_O$ (see Notes 1 and 2) Input clamp current, $I_{IK}$ ( $V_I < 0$ ) Output clamp current, $I_{OK}$ ( $V_O < 0$ ) Continuous output current, $I_O$ Continuous current through $V_{CC}$ or GND	-0.5 V to 6.5 V 0.5 V to V <sub>CC</sub> + 0.5 V 50 mA 50 mA ±50 mA ±100 mA
Continuous output current, I <sub>O</sub>	±50 mA
Package thermal impedance, $\theta_{JA}$ (see Note 3): D package	113°C/W
PW package Storage temperature range, T <sub>stg</sub>	

<sup>+</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The value of V<sub>CC</sub> is provided in the recommended operating conditions table.

3. The package thermal impedance is calculated in accordance with JESD 51.

### recommended operating conditions (see Note 4)

			MIN	MAX	UNIT		
Vaa	Supplyveltege	Operating	1.65	3.6	V		
VCC	Supply voltage	Data retention only	1.5		v		
		V <sub>CC</sub> = 1.65 V to 1.95 V	0.65 × V <sub>CC</sub>				
VIH	High-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7		V		
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2				
		V <sub>CC</sub> = 1.65 V to 1.95 V		$0.35 \times V_{CC}$			
VIL	Low-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		0.7	V		
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$		0.8	1		
VI	Input voltage		0	5.5	V		
VO	Output voltage		0	VCC	V		
	High-level output current	V <sub>CC</sub> = 1.65 V		-4			
La		V <sub>CC</sub> = 2.3 V		-8	mA		
ЮН		V <sub>CC</sub> = 2.7 V		-12			
		$V_{CC} = 3 V$		-24			
		V <sub>CC</sub> = 1.65 V		4			
1	Low-level output current	V <sub>CC</sub> = 2.3 V		8	1.		
IOL		V <sub>CC</sub> = 2.7 V		12	mA		
	V <sub>CC</sub> = 3 V			24			
$\Delta t/\Delta v$	Input transition rise or fall rate	-	0	10	ns/V		
TA	Operating free-air temperature		-40	85	°C		

NOTE 4: All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



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PARAMETER	TEST CONDITIONS	Vcc	MIN TYP <sup>†</sup>	MAX	UNIT
	I <sub>OH</sub> = -100 μA	1.65 V to 3.6 V	V <sub>CC</sub> -0.2		
	I <sub>OH</sub> = -4 mA	1.65 V	1.2		
Maria	$I_{OH} = -8 \text{ mA}$	2.3 V	1.7		V
VOH		2.7 V	2.2		v
	$I_{OH} = -12 \text{ mA}$	3 V	2.4		
	I <sub>OH</sub> = -24 mA	3 V	2.2		
	I <sub>OL</sub> = 100 μA	1.65 V to 3.6 V		0.2	
	$I_{OL} = 4 \text{ mA}$	1.65 V		0.45	
VOL	I <sub>OL</sub> = 8 mA	2.3 V		0.7	V
	$I_{OL} = 12 \text{ mA}$	2.7 V		0.4	
	$I_{OL} = 24 \text{ mA}$	3 V		0.55	
Ц	$V_{I} = 5.5 V \text{ or GND}$	3.6 V		±5	μA
ICC	$V_{I} = V_{CC} \text{ or } GND,$ $I_{O} = 0$	3.6 V		10	μA
$\Delta I_{CC}$	One input at $V_{CC}$ – 0.6 V, Other inputs at $V_{CC}$ or GND	2.7 V to 3.6 V		500	μA
Ci	$V_{I} = V_{CC} \text{ or } GND$	3.3 V	5		pF

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

<sup>†</sup> All typical values are at  $V_{CC}$  = 3.3 V,  $T_A$  = 25°C.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = 1.8 V	$V_{CC}$ = 2.5 V $\pm$ 0.2 V		V <sub>CC</sub> = 2.7 V		V <sub>CC</sub> = 3.3 V ± 0.3 V		UNIT
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
	A or B		13.9	1	7.9		5.9	1	5.2	
<sup>t</sup> pd	A/B	Y	16.1	1	10.1		8.1	1	6.8	ns
	G		15.8	1	9.8		7.8	1	6.5	
t <sub>sk(o)</sub> ‡									1	ns

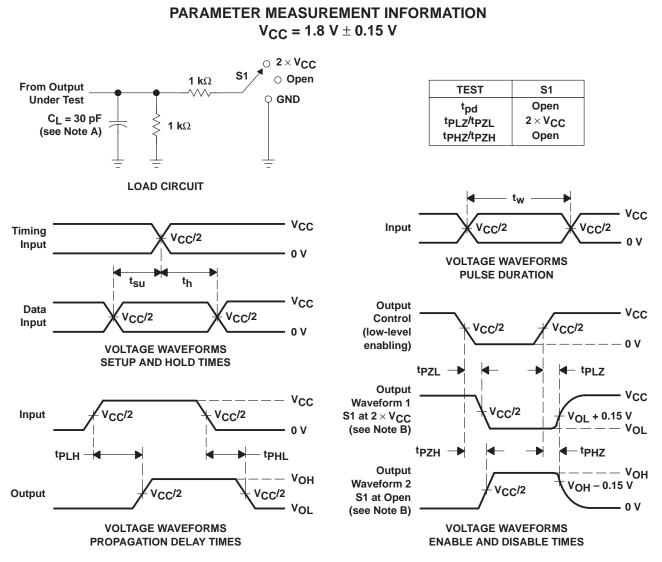
<sup>‡</sup> Skew between any two outputs of the same package switching in the same direction

## operating characteristics, $T_A = 25^{\circ}C$

PARAMETER			TEST	V <sub>CC</sub> = 1.8 V	V <sub>CC</sub> = 2.5 V	V <sub>CC</sub> = 3.3 V	UNIT
		CONDITIONS	TYP	TYP	TYP	UNIT	
Γ	C <sub>pd</sub>	Power dissipation capacitance	f = 10 MHz	14	15	16	pF



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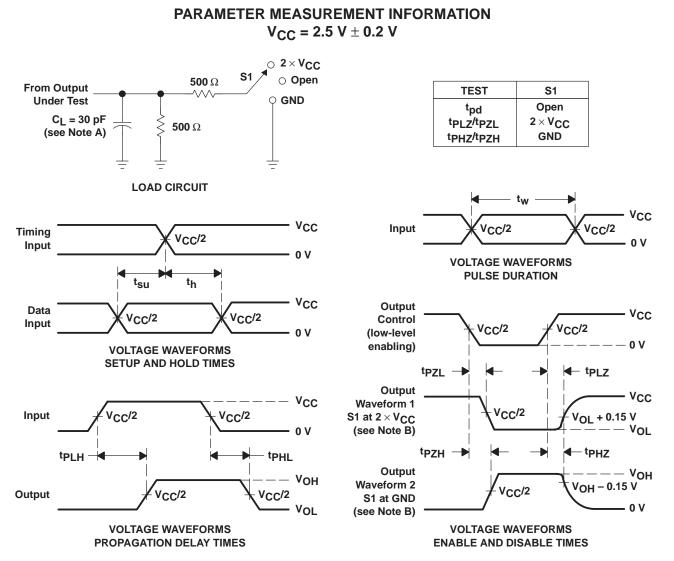
- NOTES: A. CI includes probe and jig capacitance.
  - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control. C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>f</sub>  $\leq$  2 ns, t<sub>f</sub>  $\leq$  2 ns.
  - D. The outputs are measured one at a time with one transition per measurement.

  - E. tPLZ and tPHZ are the same as tdis.
  - F. tpzL and tpzH are the same as ten.
  - G. tpl H and tpHI are the same as tpd.

### Figure 1. Load Circuit and Voltage Waveforms



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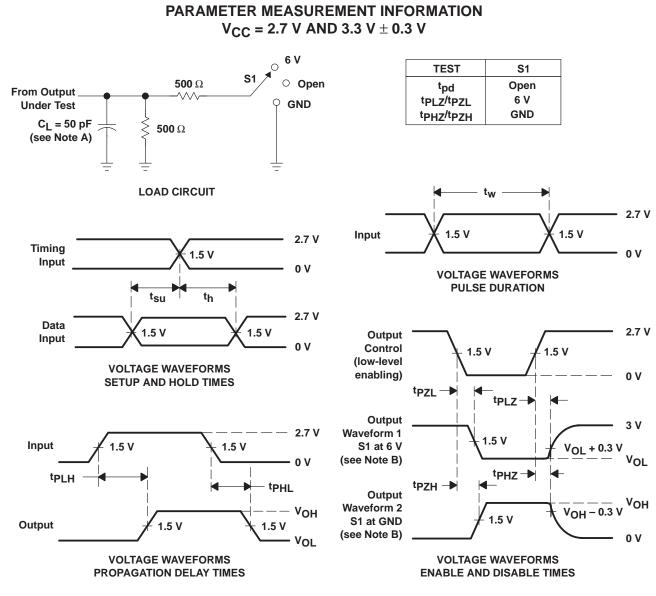
- NOTES: A. Cl includes probe and jig capacitance.
  - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control. C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>r</sub>  $\leq$  2 ns, t<sub>f</sub>  $\leq$  2 ns.

  - D. The outputs are measured one at a time with one transition per measurement.
  - E. tPLZ and tPHZ are the same as tdis.
  - F. tp7I and tp7H are the same as ten.
  - G. tpi H and tpHi are the same as tpd.

### Figure 2. Load Circuit and Voltage Waveforms



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NOTES: A. CL includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>r</sub>  $\leq$  2.5 ns, t<sub>f</sub>  $\leq$  2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F.  $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .
- G.  $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{pd}$ .

### Figure 3. Load Circuit and Voltage Waveforms



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